

## REMARKS

Claims 1-11 and 13-15 were pending and stood rejected prior to the present amendment.

Claims 1, 8, 11 and 14 are amended and claims 4 and 7 are canceled. Claims 16-18 are newly presented. Claims 1-3, 5-6, 8-11 and 13-18 are pending.

The Examiner rejected Claim 5 for antecedent basis. Due to Applicant's amendment to Claim 1, the Examiner's rejection is believed overcome.

The Examiner rejected Claims 1-3 and 9-11 under 35 U.S.C. § 103(a) as being unpatentable over U.S. Patent Application Publication 200310020852 ("Chang"), in view of U.S. Patent Publication No. 2002-182766 ("Yamamoto").

Applicant respectfully traverses the Examiner's rejection. As amended, Claim 1 recites a storage conductor which is formed on the gate insulating layer, overlapping the gate line, and electrically contacting the pixel electrode:

1. A thin film transistor array panel comprising:
  - a gate line formed on an insulating substrate including a gate electrode;
  - a gate insulating layer formed on the gate line;
  - a semiconductor layer formed on the gate insulating layer;
  - a data line formed on the gate insulating layer and including a source electrode;
  - a drain electrode formed at least in part on the semiconductor layer;
  - a color filter formed directly on the data line and the drain electrode and having a first opening exposing the drain electrode at least in part;

a light blocking layer formed on the color filter;

a passivation layer formed on the color filter and the light blocking layer and having a contact hole exposing the drain electrode through the first opening of the color filter;

a pixel electrode formed on the passivation layer and contacting the drain electrode through the contact hole;

a spacer formed on the passivation layer and disposed opposite the light blocking layer; and

a storage conductor formed on the gate insulating layer, overlapping the gate line, and electrically contacting the pixel electrode.

Such a storage conductor, which enhances voltage storage in the pixel electrode, is disclosed or suggested by neither Chang nor Yamamoto. Therefore, as amended, Claim 1 and dependent Claims 2-3 and 10 are allowable over the combined teachings of Chang and Yamamoto. Among the prior art references on record, U.S. Patent 6,862,050 ("Rho"), the Examiner has cited Rho for teaching a storage conductor. However, unlike Claim 1, Rho does not disclose a storage conductor that overlaps the gate line. Instead, Rho teaches a storage conductor (metal layer 31) that overlaps storage capacitor electrode 30. Therefore, Claim 1 is allowable over the combined teachings Chang and Yamamoto, even in view of Rho. Claim 11, which similarly recites a storage conductor, is likewise allowable over the combined teachings of Chang and Yamamoto, even in view of Rho. Accordingly, reconsideration and allowance of Claims 1-3 and 10-11 are therefore requested.

The Examiner rejected Claims 4-8 under 35 U.S.C. § 103(a) as being unpatentable over Chang and Yamamoto, further in view of Rho, citing Rho for teaching the details of a storage conductor. However, as discussed above, unlike Claim 1, Rho does not disclose a storage conductor that overlaps the gate line. Instead, Rho teaches a storage conductor (metal layer 31) that overlaps storage capacitor electrode 30. Therefore, Applicants respectfully submit that the combined teachings of Chang, Yamamoto and Rho do not disclose or suggest Claims 6 and 8. Reconsideration and allowance of

Claims 6 and 8 are therefore requested.

The Examiner rejected Claim 13 under 35 U.S.C. § 103(a) as being unpatentable over Chang and Yamamoto, in view of U.S. Patent No. 6,535,259 to Lee ("Lee"), the Examiner citing Lee for teaching a protrusion having a height less than Yamamoto's spacer. Applicant respectfully traverses the Examiner's rejection. As discussed above, Claim 11 now recites "a storage conductor formed on the gate insulating layer, overlapping the gate line, and electrically contacting the pixel electrode." This limitation is neither disclosed nor suggested by Chang, Yamamoto or Lee, individually or in combination. As Claim 13 depends from Claim 11, Claim 13 is allowable over the combined teachings of Chang, Yamamoto and Lee for the reason discussed above with respect to Claim 11. Reconsideration and allowance of Claim 13 are therefore requested.

The Examiner rejected Claim 14 under 35 U.S.C. § 103(a) as being unpatentable over U.S. Patent 6,118,505 ("Nagata"), in view of Rho. Applicant respectfully traverses the Examiner's rejection. As amended, Claim 14 also recites "[a] passivation layer comprising a film formed by chemical vapor deposition and having a dielectric constant less than 4.0" This limitation is neither disclosed nor suggested by Nagata or Rho, individually or in combination. Accordingly, Claim 13 is allowable over the combined teachings of Nagata and Rho. Reconsideration and allowance of Claim 14 are therefore requested.

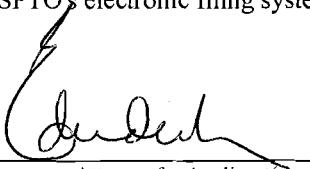
The Examiner rejected Claim 15 under 35 U.S.C. § 103(a) as being unpatentable over Nagata, in view of Rho, and further in view of Lee, the Examiner citing Lee for teaching a protrusion having a height less than Rho's spacer . Applicant respectfully traverses the Examiner's rejection. As discussed above, Claim 14 recites "[a] passivation layer comprising a film formed by chemical vapor deposition and having a dielectric constant less than 4.0" This limitation is

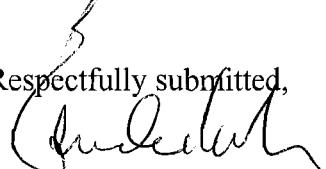
neither disclosed nor suggested by Nagata, Rho or Lee, individually or in combination. As Claim 15 depends from Claim 14, Claim 15 is therefore allowable over the combined teachings of Nagata, Rho and Lee. Reconsideration and allowance of Claim 15 are therefore requested.

Newly presented Claims 16-18 are believed likewise allowable over the prior art of record.

Accordingly, Applicant respectfully submits that claims 1-3, 5-6, 8-11 and 13-18 are now in allowable form. If the Examiner has any questions regarding the above, the Examiner is requested to call Applicants' Attorney at 408-392-9250.

The Commissioner is authorized to charge any deficiencies in fees and credit any overpayment of fees to Deposit Account No. 50-2257.

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